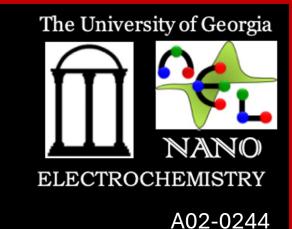


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Effect of Fast-Charging and Cycling Window on Lithium-Ion Battery Performance and Aging

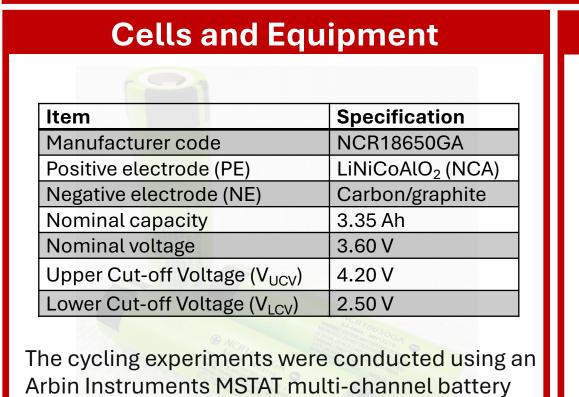
S. Venkatakrishnan and R. Ramasamy

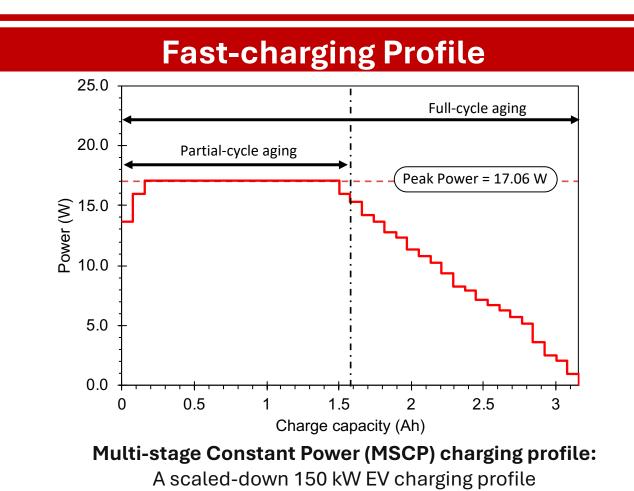
Nano Electrochemistry Laboratory, School of Chemical, Materials and Biomedical Engineering, University of Georgia, GA 30602

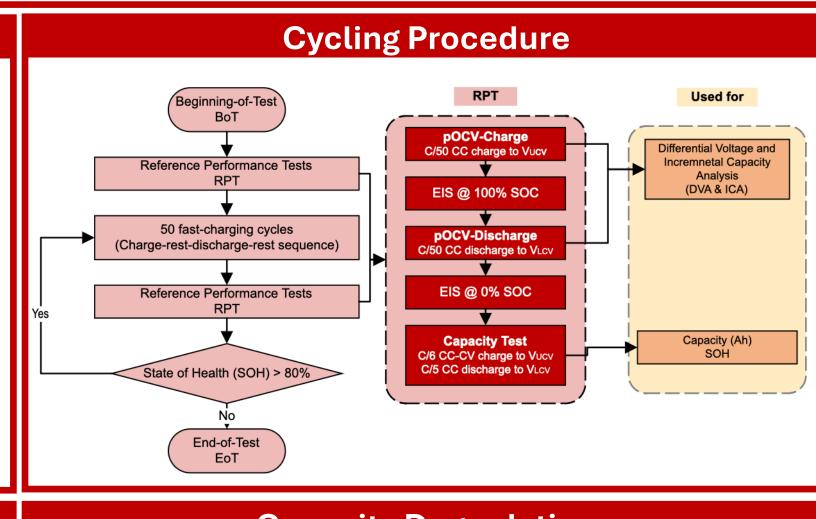


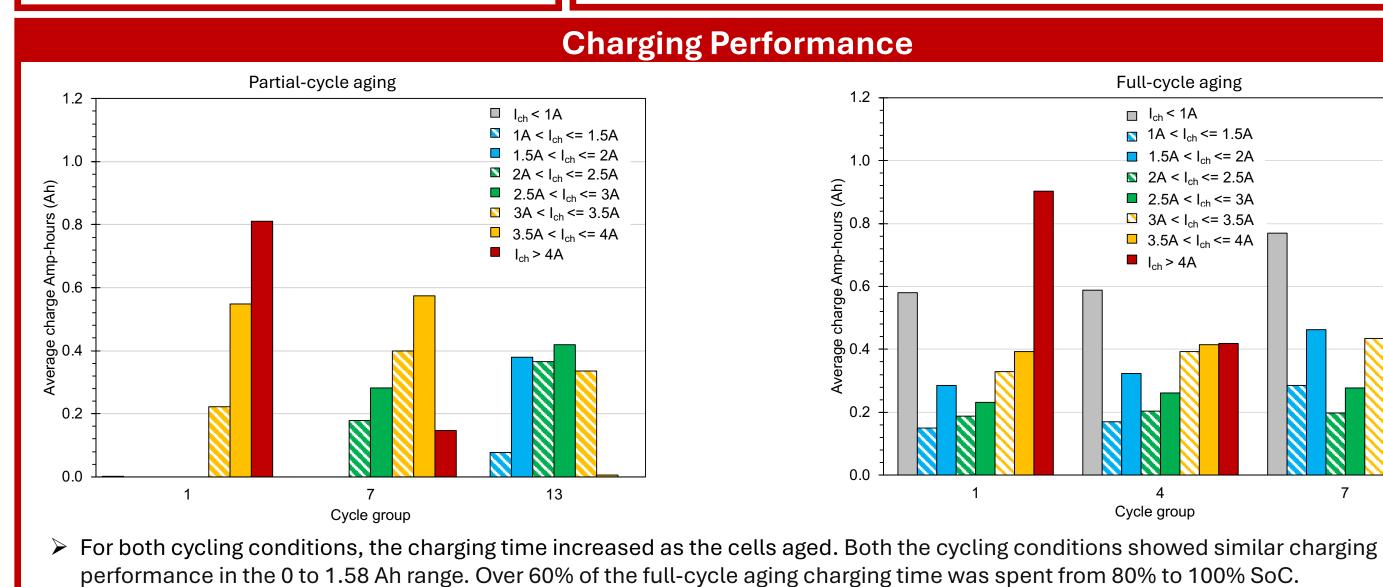
Introduction

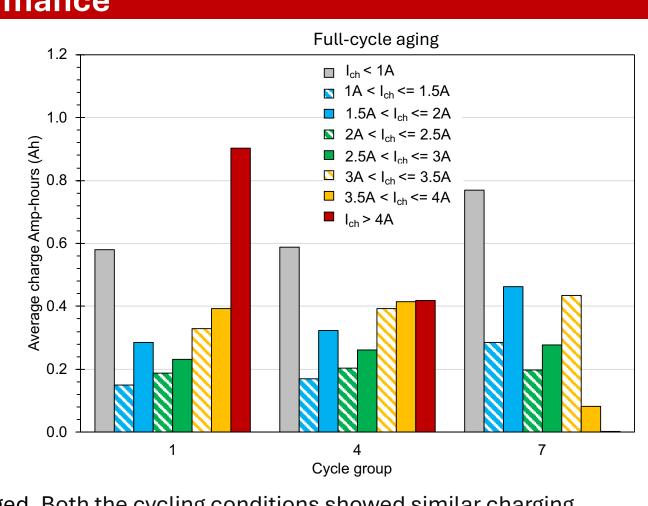
- > Traditional fast-charge aging studies focus on conventional CC-CV fast-charging profiles with a single C-rate rather than real-world profiles with varying C-rates. This study aims to bridge that gap using a scaled-down version of the 150kW EV charging profile.
- > EVs seldom operate across their full state-of-charge (SoC) range (0-100%). Investigating partial-cycle aging offers insights that better reflect actual EV usage patterns.
- > In this work, the charging performance and degradation pathway of cells cycled under two different cycling conditions, partial-cycle (0-50% SoC) and full-cycle (0-100% SoC), with the scaled-down real-world EV fast-charging profile, have been investigated. Differential voltage and incremental capacity (DV and IC) analysis have been used to identify different degradation modes.







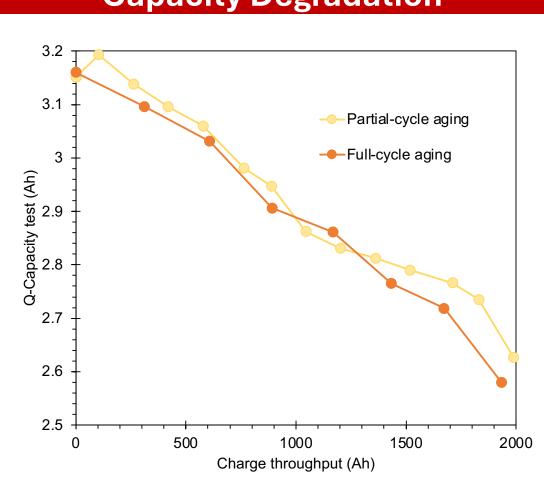




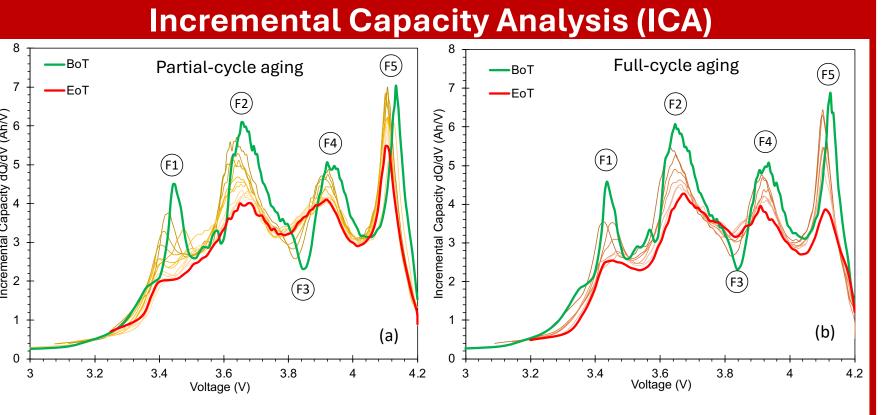


 \triangleright As the cells aged, their voltages hit V_{UCV} before reaching the target charge capacity for the respective MSCP charging steps, shifting most charging duties either to the subsequent steps or the CV phase in case of partial-cycle aging.

Capacity Degradation



> The cells used for partial-cycle and full-cycle aging completed 650 (288 FEC) and 353 (296 FEC) cycles, respectively, before reaching EoT.



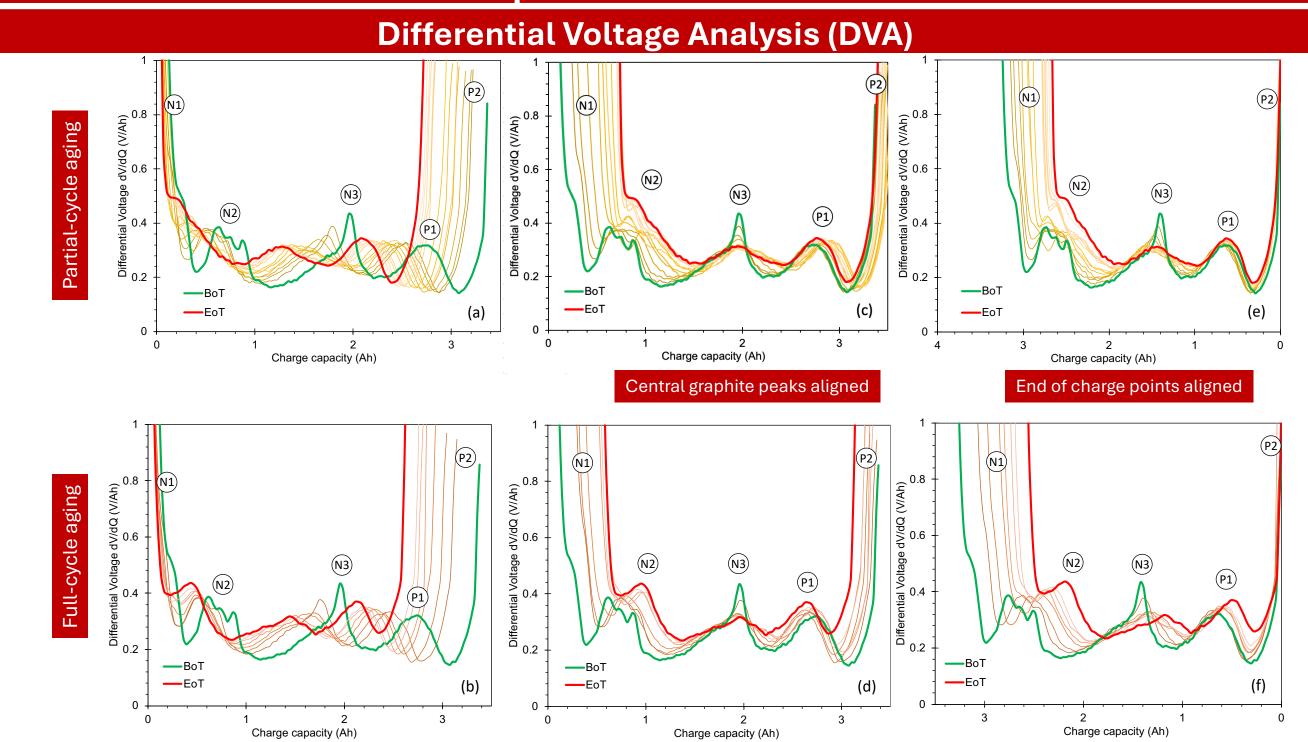
IC curves highlight phase transformations, with peaks corresponding to voltage plateaus

Partial-cycle aging:

- F1 decreased in height and eventually disappeared.
- Arch F3 decreased in intensity and shifted to lower voltages, indicating rate degradation of NE (RD F_{NE}).
- F5 remained unchanged initially but decreased in height during later stages, suggesting loss of active material of PE (LAM_{PE}) towards EoT.

> Full-cycle aging:

- F1 decreased in height but did not disappear.
- F5 consistently decreased throughout the cycling, indicating LAM_{PF} was present throughout the test.

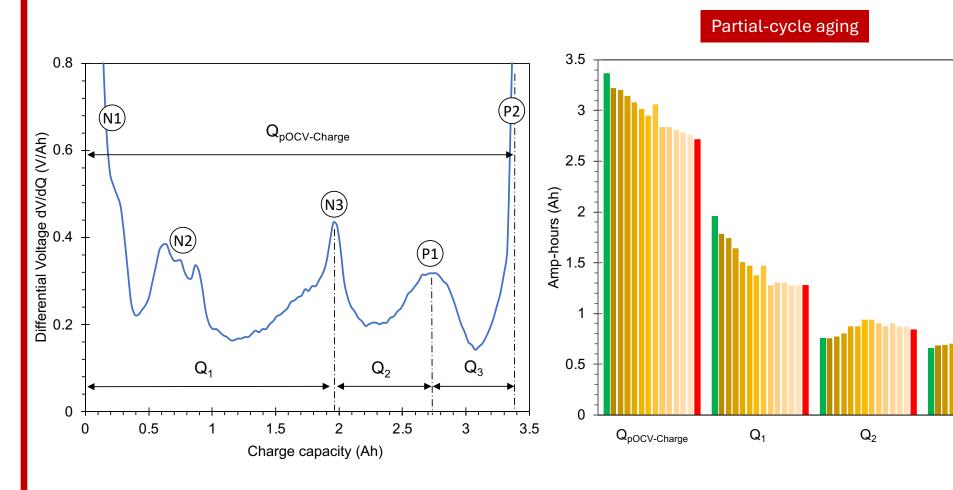


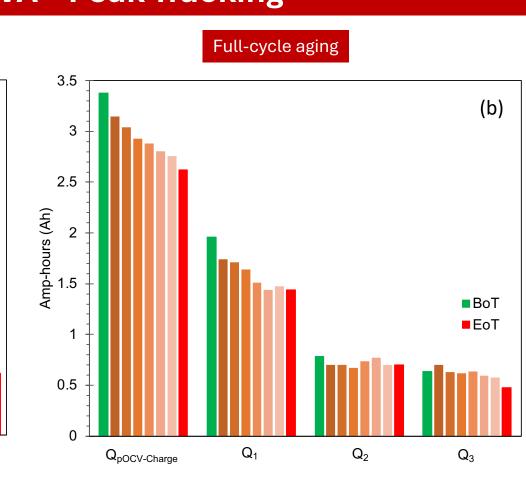
- > The peak N3 broadened, while N2 either smeared into a single peak (full-cycle aging) or disappeared (partial-cycle aging). This broadening and disappearance of peaks are attributed to the heterogeneity of lithium distribution.
- > The DVA spectra to the left of N3 appear compressed, indicating a loss in capacity at lower SOCs. The DVA spectra to the right of N3 remain stable in partial-cycle aging but appear compressed in full-cycle aging.
- > The dV/dQ values increased more drastically to the left of N3 than to the right, suggesting increased polarization of the NE, which is likely due to higher local resistance.

DVA - Peak Tracking

(a)

■BoT





- \triangleright Q₁ and Q₃: Degradation indicator capacity for NE and PE, respectively; Q₂ offers insights into electrode balance
- \triangleright For both cycling conditions, the trends of Q_1 largely resemble $Q_{pOCV-charge}$, indicating the LAM_{NE} as a significant contributor to cell degradation.
- \triangleright For full-cycle aging, the decreasing trend of Q_3 is not as prominent as Q_1 but persists until the end of the tests, suggesting LAM_{PE} from the very early stages of cycling.

Conclusion

- Both cycling experiments exhibited similar overall capacity fade trends, but the underlying causes differed.
- The DV-IC analysis revealed that LAM $_{NE}$ was pivotal in capacity fade for both cycling experiments.
 - LAM_{PE} was observed alongside LAM_{NE} throughout the cycling experiment for full-cycle aging, but it was only observed towards the EoT in partial-cycle aging.
- > Additionally, a decrease in the homogeneity of lithium distribution within the negative electrode and kinetic rate degradation of the negative electrode (in the case of partial-cycle aging) were evident.